

Notice of References Cited

Application/Control No.

09/557,961

Applicant(s)/Patent Under
Reexamination
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Examiner

Donghee Kang

Art Unit

2811

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*		Document Number		Date MM-YYYY	Name	Classification	
		Country	Code-Number-Kind Code				
	A	US-	5,990,500-A	Nov.23,19 99	Okazaki	257	99
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	K	US-	-				
	L	US-	-				
	M	US-	-				

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		Country	Code-Number-Kind Code					
	N	-	-					
	O	-	-					
	P	-	-					
	Q	-	-					
	R	-	-					
	S	-	-					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages					
	U	Kim et al., "Cr/Ni/Au ohmic contacts to the moderately doped p- and n-GaN", Mat. Rss. Soc. Symp. Proc. Vol. 449, 1997, pp 1061-1065.					
	V	Trexler et al., "Comparison of Ni/Au, Pd/Au, and Cr/Au metallizations for ohmic contacts to p-GaN", Mat. Rss. Soc. Symp. Proc. Vol. 449, 1997, pp 1061-1065.					
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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